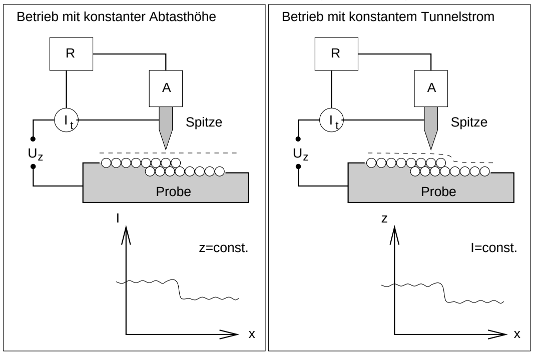
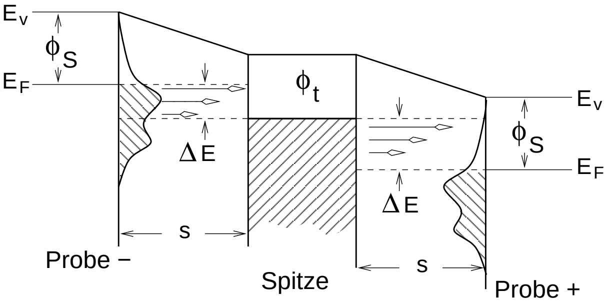
Tunnelmikroskopie (STM)

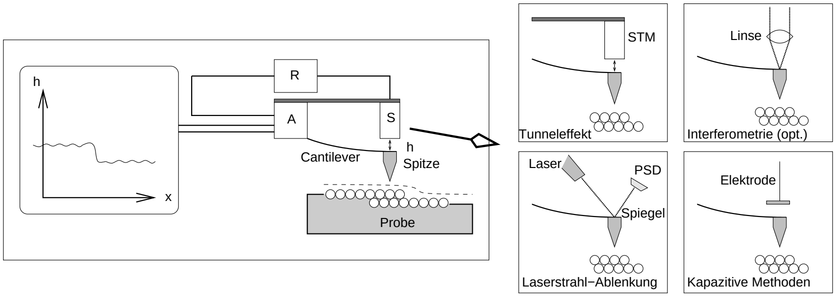


Betriebsarten



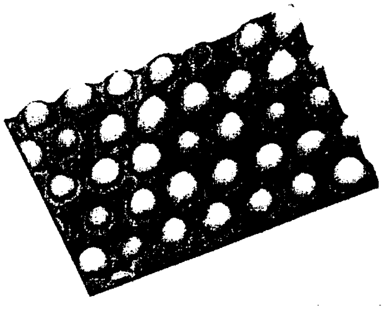
Messgrössen

Kraftmikroskopie (AFM)

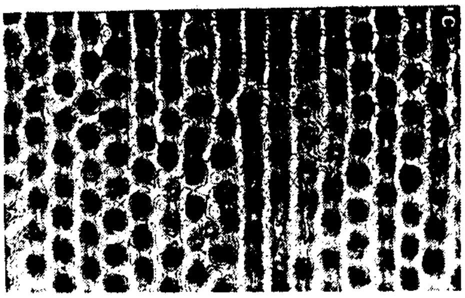


Prinzip der AFM

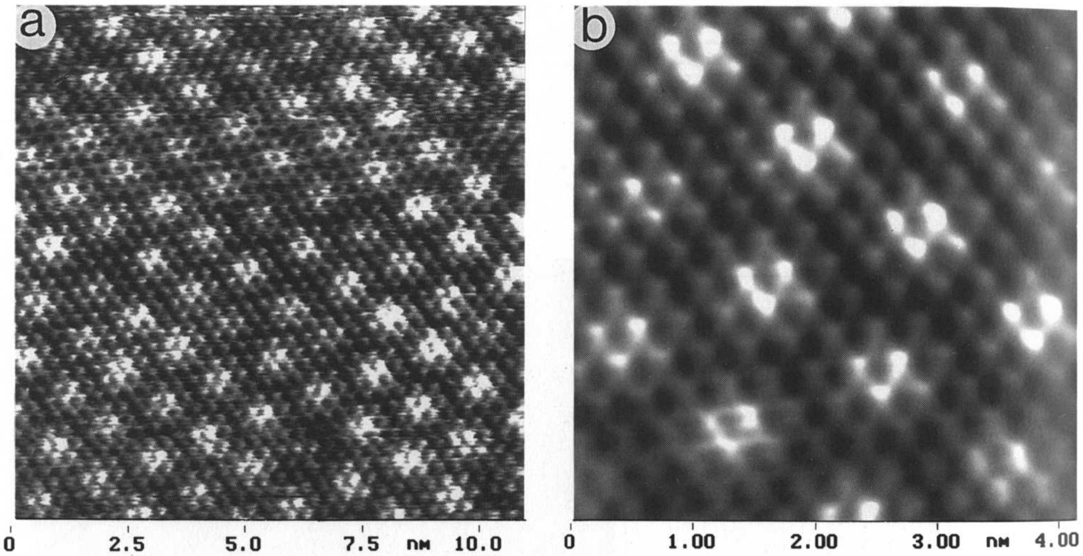
Beispiele:



RTM-Aufnahme einer Si(111)- Oberfläche (I_T = 2 nA; U = 1.5 V)



Atomare Auflösung einer Graphitoberfläche



STM-Bild von 1T-TaS$_2$ (I=6 nA, V=-10 mV) links: Originalbild der $\sqrt{13}$x$\sqrt{13}$-Überstruktur; rechts: nach FFT-Filterung)